

Data sheet acquired from Harris Semiconductor SCHS096

CMOS FIFO Register

4 Bits X 16 Words

High-Voltage Types (20-Volt Rating)

CD40105B is a low-power first-infirst-out (FIFO) "elastic" storage register that can store 16 4-bit words. It is capable of handling input and output data at different shifting rates. This feature makes it particularly useful as a buffer between asynchronous systems.

Each word position in the register is clocked by a control flip-flop, which stores a marker bit. A "1" signifies that the position's data is filled and a "0" denotes a vacancy in that position. The control flip-flop detects the state of the preceding flip-flop and communicates its own status to the succeeding flip-flop. When a control flip-flop is in the "0" state and sees a "1" in the preceding flip-flop, it generates a clock pulse that transfers data from the preceding four data latches into its own four data latches and resets the preceding flip-flop to "0". The first and last control flip-flops have buffered outputs. Since all empty locations "bubble" automatically to the input end, and all valid data ripple through to the output end, the status of the first control flip-flop (DATA-IN READY) indicates if the FIFO is full, and the status of the last flip-flop (DATA-OUT READY) indicates if the FIFO contains data. As the earliest data are removed from the bottom of the data stack (the output end), all data entered later will automatically propagate (ripple) toward the output.

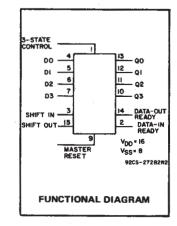
Loading Data — Data can be entered whenever the DATA-IN READY (DIR) flag is high, by a low to high transition on the SHIFT-IN (SI) input. This input must go low momentarily before the next word is accepted by the FIFO. The DIR flag will go low momentarily, until the data have been trans-

Features:

- Independent asynchronous inputs and outputs
- 3-state outputs Expandable in either direction
- Status indicators on input and output Reset capability
- Standardized, symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- 5-V, 10-V, and 15-V parametric ratings
- Maximum input current of 1 µA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range): 1 V at V_{DD} = 5 V
 2 V at V_{DD} = 10 V
 2.5 V at V_{DD} = 15 V
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

ferred to the second location. The flag will remain low when all 16-word locations are filled with valid data, and further pulses on the SI input will be ignored until DIR goes high.

Unloading Data — As soon as the first word has rippled to the output, DATA-OUT READY (DOR) goes high, and data can be removed by a falling edge on the SO input. This falling edge causes the DOR signal to go low while the word on the output is dumped and the next word moves to the output. As long as valid data are available in the FIFO, the DOR signal will go high again signifying that the next word is ready at the output. When the FIFO is empty, DOR will remain low, and any further commands will be ignored until a "1" marker ripples down to the last control register,



Applications:

CD40105B Types

- Bit rate smoothing
- CPU/terminal buffering
- Data communications
- Peripheral buffering
- Line printer input buffers
- Auto dialers
- CRT buffer memories
- Radar data acquisition

when DOR goes high. Unloading of data is inhibited while the 3-state control input is high. The 3-state control signal should not be shifted from high to low (data outputs turned on) while the SHIFT-OUT is at logic 0. This level change would cause the first word to be shifted out (unloaded) immediately and the data to be lost.

Cascading — The CD40105B can be cascaded to form longer registers simply by connecting the DIR to SO and DOR to SI. In the cascaded mode, a MASTER RESET pulse must be applied after the supply voltage is turned on. For words wider than 4 bits, the DIR and the DOR outputs must be gated together with AND gates. Their outputs drive the SI and SO inputs in parallel, if expanding is done in both directions (see Figs. 3 and 15).

3-State Outputs — In order to facilitate data busing, 3-state outputs are provided on the data output lines, while the load condition of the register can be detected by the state of the DOR output.

Master Reset — A high on the MASTER RESET (MR) sets all the control logic marker bits to "0". DOR goes low and DIR goes high. The contents of the data register are not changed, only declared invalid, and will be superseded when the first word is loaded. The shift-in must be low during Master Reset.

The CD40105B types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

MAXIMUM RATINGS, Absolute-Maximum Values: DC SUPPLY-VOLTAGE RANGE, (VDD) Voltages referenced to VSS Terminal) VOLTAGE RANGE, ALL INPUTS DC INPUT VOLTAGE RANGE, ALL INPUTS DC INPUT CURRENT, ANY ONE INPUT # 10mA POWER DISSIPATION PER PACKAGE (PD): For TA = -55°C to +100°C For TA = +100°C to +125°C Derate Linearity at 12mW/°C to 200mW DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package Types) 100mW OPERATING-TEMPERATURE RANGE (TA) STORAGE TEMPERATURE RANGE (Tatg) -65°C to +150°C LEAD TEMPERATURE (DURING SOLDERING): At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max +265°C

RECOMMENDED OPERATING CONDITIONS at 25°C, Except as Noted

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V _{DD}	LIM	UNITS	
	(V)	Min.	Max.	
Supply-Voltage Range (For T _A = Full Package – Temperature Range)) <u>.</u>	3	18	٧
Shift-In or Shift-Out Rate	5 10 15	- , 	1.5 3 4	MHz
Shift-In Pulse Width (Pin 3)	5 10 15	200 80 60		ns
Shift-Out Pulse Width (Pin 15)	5 10 15	180 75 55	-	ns
Shift-In or Shift-Out Rise Time	5 10 15		15 15 15	μs
Shift-In Fall Time	5 10 15	_ _ _	15 15 15	μs
Shift-Out Fall Time	5 10 15	- - -	15 5 5	μς
Data Hold Time	5 10 15	350 150 120	- :	ns
Master Reset Pulse Width	5 10 15	220 90 60	_ 	ns

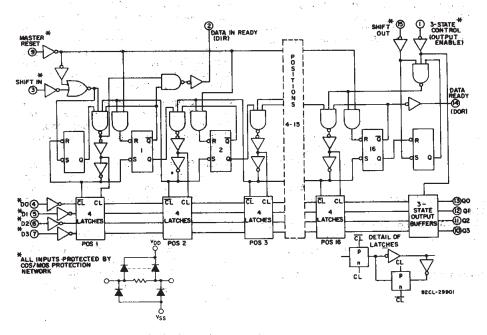


Fig. 1 - Logic diagram for the CD401058.

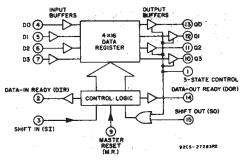


Fig. 2 - CD40105B functional block diagram.

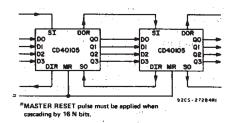


Fig. 3 - Expansion, 4-bits wide-by-16 N-bits long.

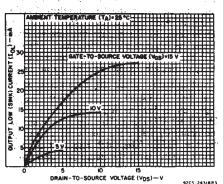


Fig. 4 — Typical output low (sink) current characteristics.

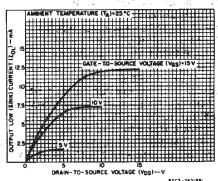


Fig. 5 – Minimum output low (sink) current characteristics.

CHARAC- TERISTIC	CON	DITIO	NS	LIMITS AT INDICATED TEMPERATURES (°C)							
	v _o	VIN	v _{DD}						+25		S
	(V)	(V)	(V)		-40	+85	+125	Min.	Тур.	Max.	
Quiescent		0,5	.5	5	5	150	150		0.04	5	
Device	_	0,10	-10	10	10	300	300	_	0.04	10	μА
Current,		0,15	15	20	20	600	600	_	0.04	20	
DD Max.	_	0,20	20	100	100	3000	3000	-	80.0	100	
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-	
(Sink) Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	_	
I _{OL} Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	_	
Output High (Source) Current, IOH Min.	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	_	mA
	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	-	
	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	-	
	13.5	0,15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8	_	
Output Voltage:		0,5	5		-0	.05	_	0	0.05		
Low-Level,	, <u> </u>	0,10	10		.0	.05	-	0	0.05	1	
V _{OL} Max.	_	0,15	15		0	.05	_	0	0.05] v	
Output	_	0,5	5		4.	.95		4.95	5	_	
Voltage:	_	0,10	10		9	.95	9.95	10	_		
High-Level, VOH Min.	_	0,15	15		14	.95	14.95	15	-		
Input Low	0.5,4.5	_	5			1.5		-	-	1.5	
Voltage	1,9	_	10			3			-	3	
VIL Max.	1.5,13.5	_	15			4		-	_	4	V
Input High	0.5,4.5	_	5			3.5		3.5	_	-	
Voltage,	1,9	_	10			7		7	-	-	
V _{IH} Min.	1.5,13.5	_	15			11		11	_	-	1
Input Current		0,18	18	±0.1	±0.1	±1	±1	-	±10-5	±0.1	μΑ
3-State Output Leakage Current IOUT Max.	0,18	0,18	18	±0.4	±0.4	±12	±12	-	±10 ⁻⁴	±0.4	μ£

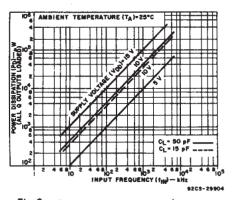


Fig. 9 — Typical dynamic power dissipation as a function of frequency.

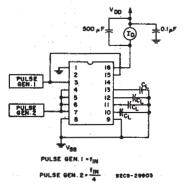


Fig. 10 – Dynamic power dissipation test circuit.

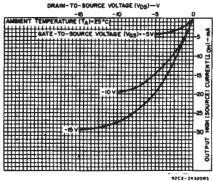


Fig. 6 - Typical output high (source) current characteristics.

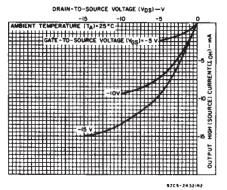


Fig. 7 — Minimum output high (source) current characteristics.

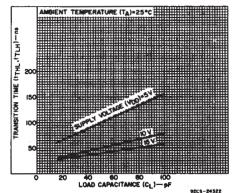


Fig. 8 - Typical transition time as a function of load capacitance.

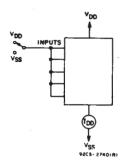


Fig. 11 — Quiescent-device-current test circuit.

CD40105B Types

DYNAMIC ELECTRICAL CHARACTERISTICS at T $_A$ = 25°C; Input t $_r$, t $_f$ = 20 ns, C $_L$ = 50 pF, R $_L$ = 200 k Ω

CHARACTERISTIC	TEST CONDI			UNITS		
		V _{DD} (V)	Min.	Тур	Max.	
Propagation Delay Time: Shift-Qut or Reset to Data-Out Ready, tpHL		5 10 15		185 90 65	370 180 130	ns
Shift-In to Data-In Ready, tpHL		5 10 15	1 1	160 65 45	320 130 90	ns
Shift-Out to Q _n Out,		5 10 15	- -	210 100 70		ns
3-State Control to Data Out Note 1 tpZH, tpZL		5 10 15	,	140 60 40	280 120 80	ns
tPHZ, tPLZ		5 10 15	1 1 1	100 50 40	200 100 80	ns
Ripple-Through Delay Input to Output, ^t PLH		5 10 15	1 1 1	2 1 0.7	4 2 1.4	μs
Transition Time, t _{THL} , t _{TLH}		5 10 15	1 1-1	100 50 40	200 100 80	ns
Maximum Shift-In or Shift-Out Rate,		5 10 15	1.5 3 4	3 6 8	1, 1-1	МНz
Minimum Shift-In Pulse Width, (Pin 3) tw		5 10 15	1 1 1	100 40 30	200 80 60	ns
Minimum Shift-Out Pulse Width, (Pìn 15) ^t WL		5 10 15	- -	90 35 25	180 75 55	n s
Maximum Shift-In or Shift-Out Rise Time, t _r		5 10 15	1 1 1	·	15 15 15	μς
Maximum Shift-In Fall Time, t _f		5 10 15	1 1	1 1 1	15 15 15	μs
Maximum Shift-Out Fall Time, t		5 10 15	1 1	1 1	15 5 5	μs
Minimum Data Setup Time, t _{SU}		5 10 15		1 +	0 0	ns
Minimum Data Hold Time, t _H		5 10 15	1 1	175 75 60	350 150 120	ns
Data-In Ready Pulse Width, t _{WL}		5 10 15	1 -	260 100 70	520 200 140	ns
Data-Out Ready Pulse Width, twL (Pin 14)		5. 10 15	1, 1-1	220 90 65	440 180 130	ns
Minimum Master Reset Pulse Width, ^t WH		5 10 15	 - -	100 45 30	200 90 60	ns
Input Capacitance C _{IN}	(Any Input)	_	_	5	7.5	pF

Note 1: The Output Enable Line (Pin 1) should be low for limits specified.

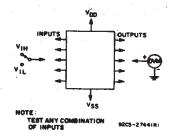


Fig. 12 - Input-voltage test circuit.

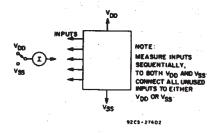
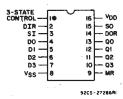


Fig. 13 - Input current test circuit.



TERMINAL ASSIGNMENT

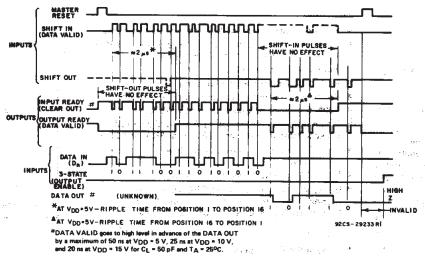


Fig. 14 — Timing diagram for the CD40105B.

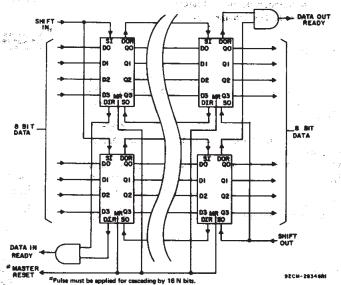
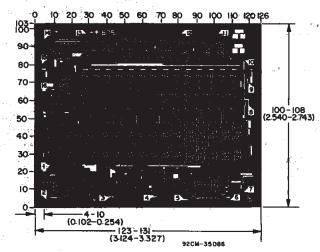


Fig. 15 - Expansion, 8-bits-wide-by-16 N-bits long using CD40105.



Dimension and pad layout for CD40105B.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10⁻³ inch).





26-Sep-2005

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
CD40105BE	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	Level-NC-NC-NC
CD40105BF	ACTIVE	CDIP	J	16	1	TBD	Call TI	Level-NC-NC-NC
CD40105BF3A	ACTIVE	CDIP	J	16	1	TBD	Call TI	Level-NC-NC-NC

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

14 LEADS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

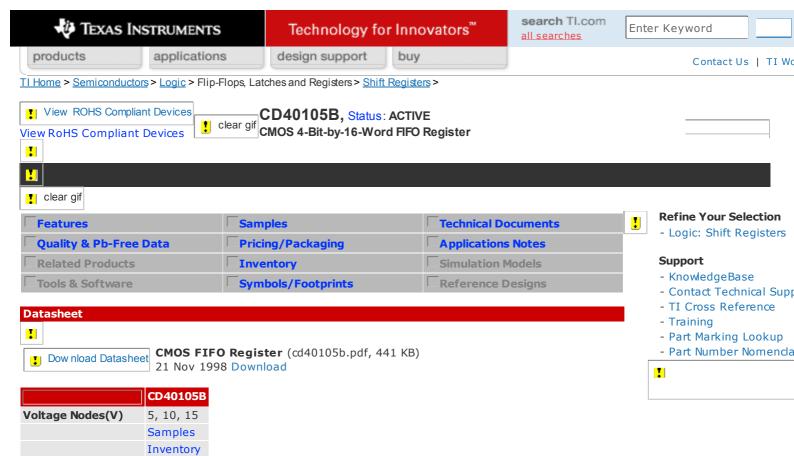
Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
		Telephony	www.ti.com/telephony
		Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments

Post Office Box 655303 Dallas, Texas 75265

Copyright © 2005, Texas Instruments Incorporated



Product Information

Features

Save this to your personal library

Independent asynchronous inputs and outputs

3-state outputs

Expandable in either direction

Status indicators on input and output

Reset capability

Standardized, symmetrical output characteristics

100% tested for quiescent current at 20 $\mbox{\ensuremath{\text{V}}}$

5-V, 10-V, and 15-V parametric ratings

Maximum input current of 1 uA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C

Noise margin (over full package-temperature range): 1V at V_{DD} = 5V, 2V at V_{DD} = 10 V, 2.5 V at V_{DD} = 15 V

Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications

- Bit rate smoothing CPU/terminal buffering
- Data communications
- Peripheral buffering
- Line printer input buffers
- Auto dialers
- CRT buffer memories
- Radar data acquisition

Description

CD40105B is a low-power first-in-first-out (FIFO) "elastic" storage register that can store 16 4-bit words. It is capable of handling input and output data at different shifting rates. This feature makes it particularly useful as a buffer between asynchronous systems.

Each word position in the register is clocked by a control flip-flop, which stores a marker bit. A "1" signifies that the position's data is filed and a "0" denotes a vacancy in that position. The control flip-flop detects the state of the preceding flip-flop and communicates its own status to the succeeding flip-flop. When a control flip-flop is in the "0" state and sees a "1" in the preceding flip-flop, it generates a clock pulse that transfers data from the preceding four data latches into its own four data latches and resets the preceding flip-flop to "0". The first and last control flip-flops have buffered outputs. Since all empty locations "bubble" automatically to the input end, and all valid data ripple through to the output end, the

status of the first control flip-flop (DATA-IN READY) indicates if the FIFO is full, and the status of the last flip-flop (DATA-OUT READY) indicates if the FIFO contains data. As the earliest data are removed from the bottom of the data stack (the output end), all data entered later will automatically propagate (ripple) toward the output.

Loading Data - Data can be entered whenever the DATA-IN READY (DIR) flag is high, by a low to high transition on the SHIFT-IN (SI) input. This input must go low momentarily before the next word is accepted by the FIFO. The DIR flag will go low momentarily, until the data have been transferred to the second location. The flag will remian low when all 16-word locations are filled with valid data, and further pulses on the SI input will be ignored until DIR goes high.

Unloading Data - As soon as the first work has rippled to the output, DATA-OUT READY (DOR) goes high, and data can be removed by a falling edge on the SO input. This falling edge causes the DOR signal to go low while the word on the output is dumped and the next word moves to the output. As long as valid data are available in the FIFO, the DOR signal will go high again signifying that the next word is ready at the output. When the FIFO is empty, DOR will remain low, and any further commands will be ignored until a "1" marker ripples down to the last control register, when DOR goes high. Unloading of data is inhibited while the 3-state control input is high. The 3-state control signal should not be shifted from high to low (data outputs turned on) while the SHIFT-OUT is a logic 0. This level change would cause the first word to be shifted out (unloaded) immediately and the data to be lost.

Cascading - The CD40105B can be cascaded to form longer registers simply by connecting the DIR to SO and DOR to SI. In the cascaded mode, a MASTER RESET pulse must be applied after the supply voltage is turned on. For words wider than 4 bits, the DIR and the DOR outputs must be gated together with AND gates. Their outputs drive the SI and SO inputs in paralled, if expanding is done in both directions (see Figs. 3 and 15).

3-State Outputs - In order to facilitate data busing, 3-state outputs are provided on the data output lines, while the load condition of the register can be detected by the state of the DOR output.

Master Reset - A high on the MASTER RESET (MR) sets all the contol logic marker bits to "0". DOR goes low and DIR goes high. The contents of the data register are not changed, only declared invalid, and will be superseded when the first word is loaded. The shift-in must be low during Master Reset. The CD40105B types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

Pricing/Packaging/CAD Design Tools/Samples									
	Price Packaging		CAD Design Tools	Samples					
Device	Status	Temp (°C)	Budget Price (\$US) QTY	Industry Standard (TI Pkg) Pins	Top Side Marking	Standard Pack Quantity	Footprints	Samples	
CD40105BE	ACTIVE	-55 to 125	1.12 1KU	PDIP (N) 16	View	25		Contact TI Distributor or Sales Office	
CD40105BF	ACTIVE	-55 to 125	3.70 1KU	CDIP (J) 16		1		Purchase Samples	
CD40105BF3A	ACTIVE	-55 to 125	4.38 1KU	CDIP (J) 16		1		Purchase Samples	

Inventory								1
		TI Inventory St	atus	Repo	orted Distri	View all Distributo		
CD40105BE	As o	of 9:55 AM GMT,	29 Nov 2005	,	As of 9:55 A	Choose a Region		
	In Stock	In Progress QTY Date	Lead Time	Region	Company	In Stock	Purchase	
	0*	1 12 Dec	10 Weeks	Americas	DigiKey	41		
		1675 20 Dec		Europe	Abacus Polar	>1k		
		>10k 16 Jan			EBV Elektronik	50		
					Spoerle	506		
CD40105BF	As	of 9:55 AM GMT,	29 Nov 2005	,	As of 9:55 A	_		
	In Stock	In Progress QTY Date	Lead Time	Region	Company	In Stock	Purchase	
	121*	279 12 Dec	8 Weeks	Americas	Avnet	90		
		8229 28 Dec						
		>10k 3 Jan						
CD40105BF3A	As o	of 9:55 AM GMT,	29 Nov 2005	,	As of 9:55 A	AM GMT	, 29 Nov 2005	
	In Stock	In Progress QTY Date	Lead Time	Region	Company	In Stock	Purchase	
	279*	8229 28 Dec	8 Weeks	Europe	Avnet- SILICA	52		
		>10k 3 Jan						

* Our information is updated daily, so please check back with us ** Lead time information is not available at this time. However, soon if this does not meet your needs. You may also contact your TI Authorized Distributor, including those listed above, for real time stock information.

our information is updated daily so please check back with us soon. Please contact your preferred TI Authorized Distributor for additional information.

Quality & Lead (Pb)-Free Data										
	Product Content MTBF/FIT Rate									
Device	Eco Plan*	Lead/Ball Finish	MSL Rating/Peak Reflow	Details	Details					
CD40105BE	Pb-Free (RoHS)	CU NIPDAU	Level-NC-NC-NC	View	View					
CD40105BF	TBD	Call TI	Level-NC-NC-NC	View	View					
CD40105BF3A	TBD	Call TI	Level-NC-NC-NC	View	View					

* The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) - please click on the Product Content Details "View" link in the table above for the latest availability information and additional product content details.

If the information you are requesting is not available online at this time, contact one of our Product Information Centers regarding the availability of this information.

Technical Documents

Datasheets Keep track of what's new

CMOS FIFO Register (cd40105b.pdf, 441 KB)

21 Nov 1998 Download

Application Notes

Semiconductor Packing Material Electrostatic Discharge (ESD) Protection (szza047.htm, 9 KB)

08 Jul 2004 Abstract

Shelf-Life Evaluation of Lead-Free Component Finishes (szza046.htm, 9 KB)

24 May 2004 Abstract

Understanding and Interpreting Standard-Logic Data Sheets (Rev. B) (szza036b.htm, 8 KB)

28 May 2003 Abstract

Understanding Buffered and Unbuffered CD4xxxB Series Device Characteristics (scha004.htm, 9 KB)

03 Dec 2001 Abstract

View Application Notes for SHIFT REGISTERS

User Guides

Signal Switch Data Book (Rev. A) (scdd003a.pdf, 19732 KB)

14 Nov 2003 Download

LOGIC Pocket Data Book (scyd013.pdf, 4835 KB)

05 Dec 2002 Download

View User Guides for SHIFT REGISTERS

More Literature

Logic Selection Guide 2005 (Rev. X) (sdyu001x.pdf, 6909 KB)

15 Mar 2005 Download

Military Semiconductors Selection Guide 2004-2005 (Rev. D) (sgyc003d.pdf, 964 KB)

10 Aug 2004 Download

Logic Cross-Reference (Rev. A) (scyb017a.pdf, 2938 KB)

07 Oct 2003 Download

View More Literature for SHIFT REGISTERS

Products | Applications | Design Support | Buy | Contact Us | TI Worldwide | my.TI Login | All Searches | Company Info | Press Releases | RSS | Site Map

© Copyright 1995-2005 Texas Instruments Incorporated. All rights reserved. Trademarks | Privacy Policy | Terms of Use